

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (U-MOSII)

# TPC8203

Lithium Ion Battery Applications

Portable Equipment Applications

Notebook PC Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance :  $R_{DS(ON)} = 14 \text{ m}\Omega$  (typ.)
- High forward transfer admittance :  $|Y_{fs}| = 8 \text{ S}$  (typ.)
- Low leakage current :  $I_{DSS} = 10 \text{ }\mu\text{A}$  (max) ( $V_{DS} = 30 \text{ V}$ )
- Enhancement mode :  $V_{th} = 0.8 \sim 2.5 \text{ V}$  ( $V_{DS} = 10 \text{ V}$ ,  $I_D = 1 \text{ mA}$ )

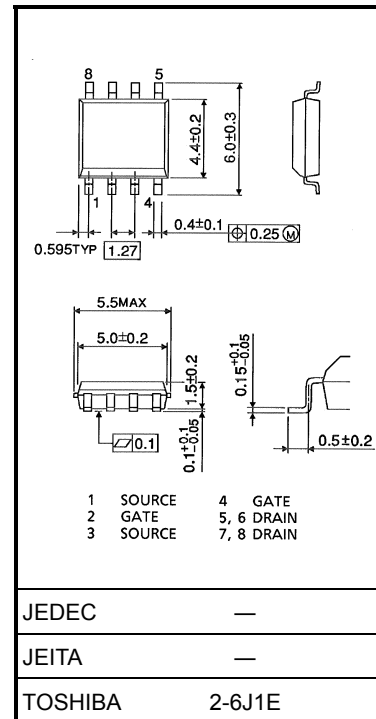
## Maximum Ratings ( $T_a = 25^\circ\text{C}$ )

Characteristics		Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	30	V
Drain-gate voltage ( $R_{GS} = 20 \text{ k}\Omega$ )		$V_{DGR}$	30	V
Gate-source voltage		$V_{GSS}$	$\pm 20$	V
Drain current	D C (Note 1)	$I_D$	6	A
	Pulse (Note 1)	$I_{DP}$	24	
Drain power dissipation ( $t = 10 \text{ s}$ ) (Note 2a)	Single-device operation (Note 3a)	$P_D(1)$	1.5	W
	Single-device value at dual operation (Note 3b)	$P_D(2)$	1.0	
Drain power dissipation ( $t = 10 \text{ s}$ ) (Note 2b)	Single-device operation (Note 3a)	$P_D(1)$	0.75	W
	Single-device value at dual operation (Note 3b)	$P_D(2)$	0.45	
Single pulse avalanche energy (Note 4)		$E_{AS}$	46.8	mJ
Avalanche current		$I_{AR}$	6	A
Repetitive avalanche energy (Note 2a, Note 3b, Note 5)		$E_{AR}$	0.10	mJ
Channel temperature		$T_{ch}$	150	$^\circ\text{C}$
Storage temperature range		$T_{stg}$	$-55 \sim 150$	$^\circ\text{C}$

Note 1, Note 2a, Note 2b, Note 3a, Note 3b, Note 4 and Note 5: See the next page.

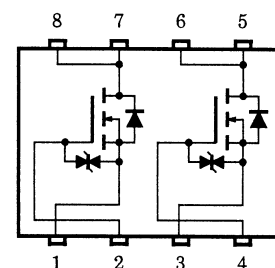
This transistor is an electrostatic-sensitive device. Please handle with caution.

Unit: mm



Weight: 0.080 g (typ.)

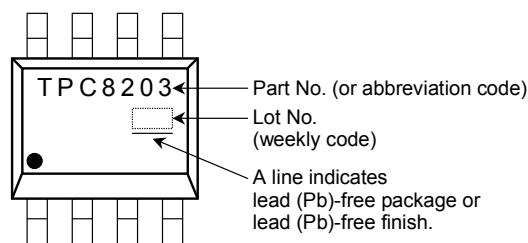
## Circuit Configuration



## Thermal Characteristics

Characteristics		Symbol	Max	Unit
Thermal resistance, channel to ambient ( $t = 10$ s) (Note 2a)	Single-device operation (Note 3a)	$R_{th(ch-a)}(1)$	83.3	$^{\circ}\text{C/W}$
	Single-device value at dual operation (Note 3b)	$R_{th(ch-a)}(2)$	125	
Thermal resistance, channel to ambient ( $t = 10$ s) (Note 2b)	Single-device operation (Note 3a)	$R_{th(ch-a)}(1)$	167	
	Single-device value at dual operation (Note 3b)	$R_{th(ch-a)}(2)$	278	

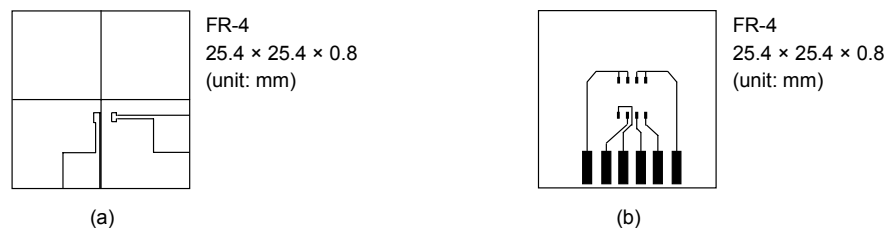
## Marking



Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:

- a) Device mounted on a glass-epoxy board (a)      b) Device mounted on a glass-epoxy board (b)



Note 3:

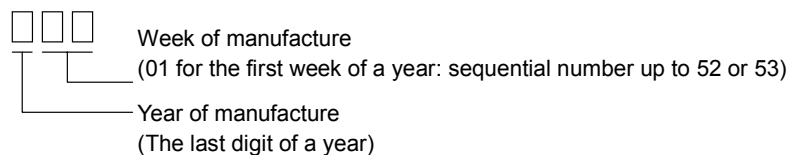
- a) The power dissipation and thermal resistance values are shown for a single device  
(During single-device operation, power is only applied to one device.)
- b) The power dissipation and thermal resistance values are shown for a single device  
(During dual operation, power is evenly applied to both devices.)

Note 4:  $V_{DD} = 24$  V,  $T_{ch} = 25^{\circ}\text{C}$  (Initial),  $L = 1.0$  mH,  $R_G = 25$   $\Omega$ ,  $I_{AR} = 6.0$  A

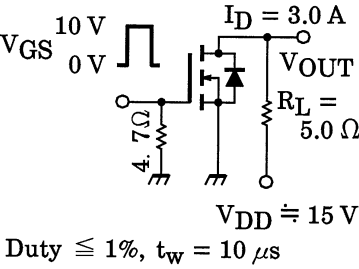
Note 5: Repetitive rating: pulse width limited by maximum channel temperature

Note 6: • on lower left of the marking indicates Pin 1.

※ Weekly code: (Three digits)

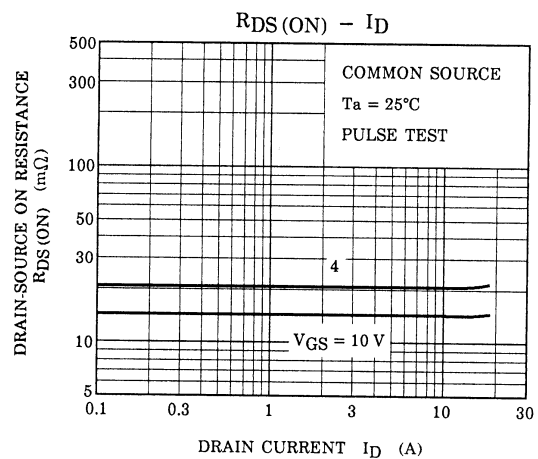
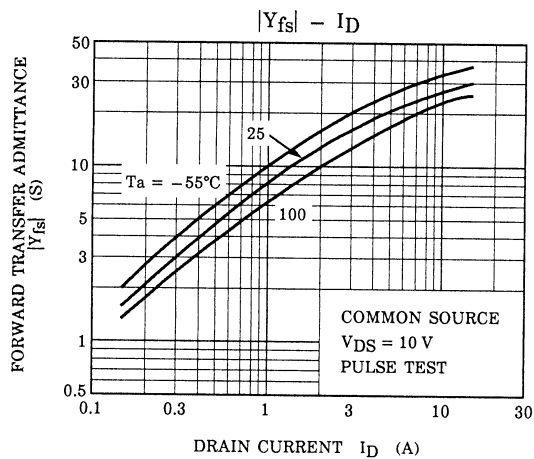
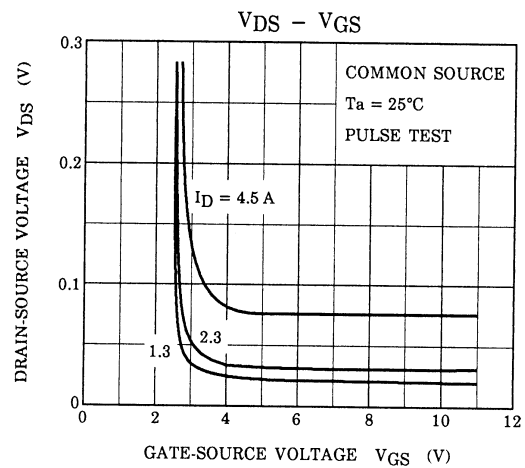
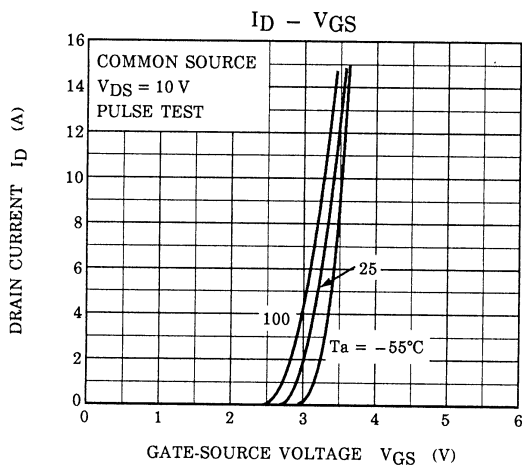
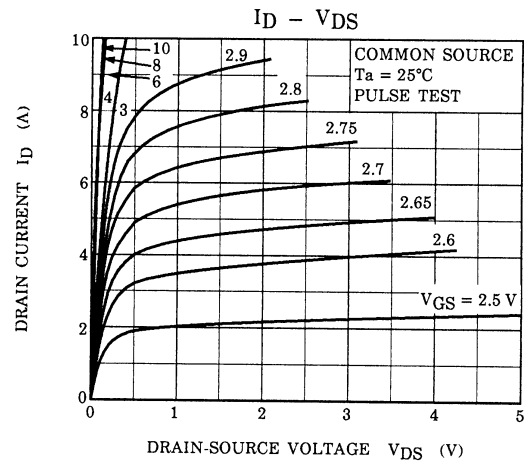
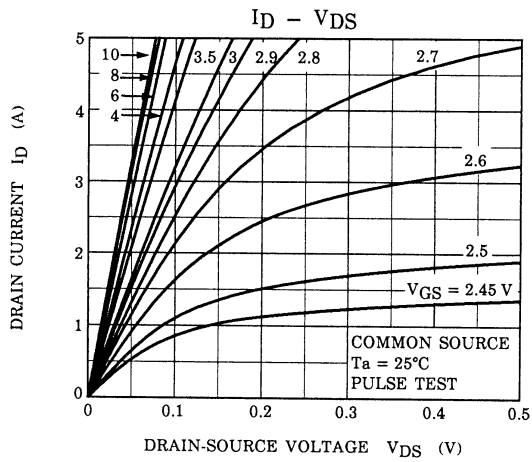


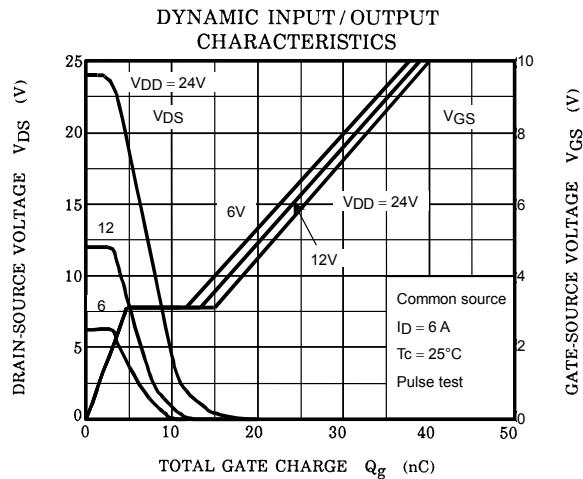
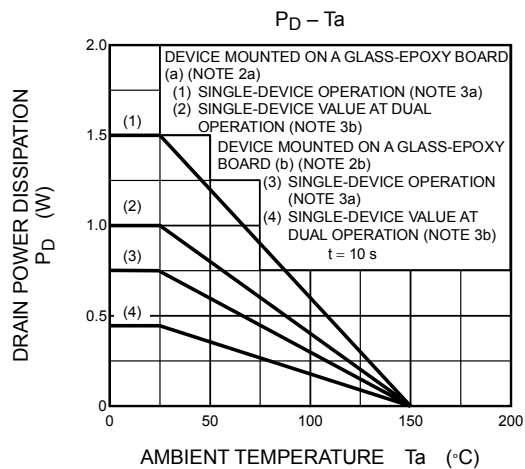
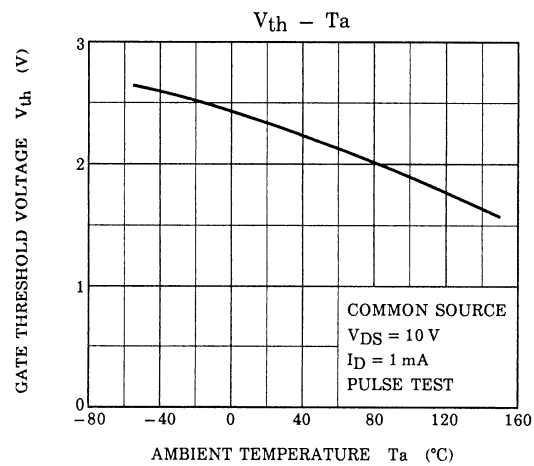
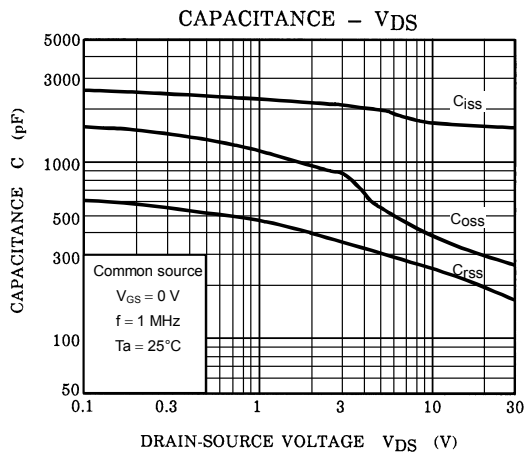
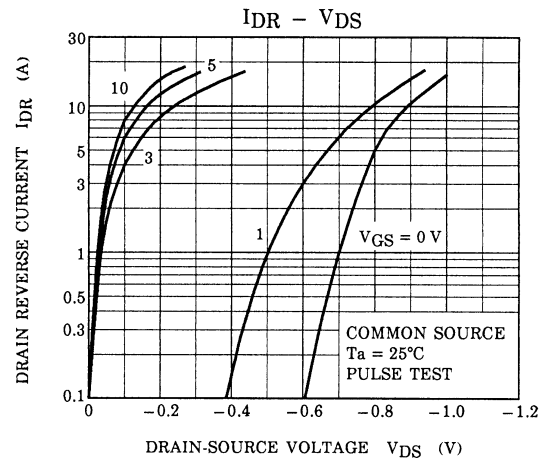
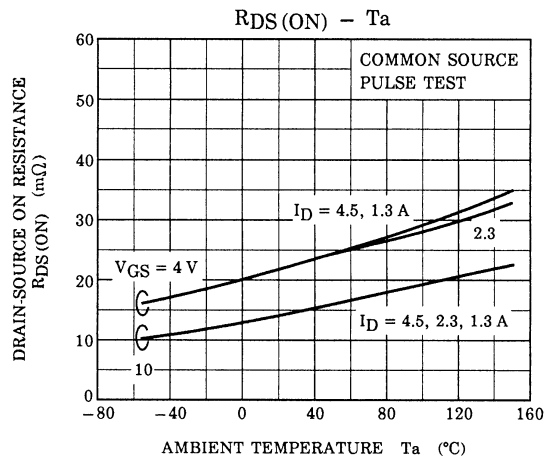
## Electrical Characteristics (Ta = 25°C)

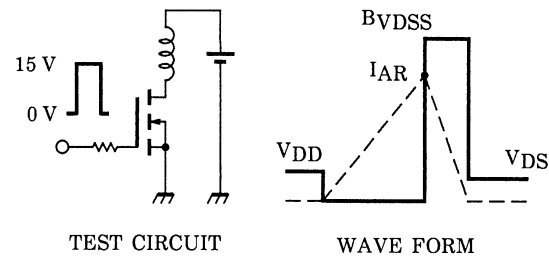
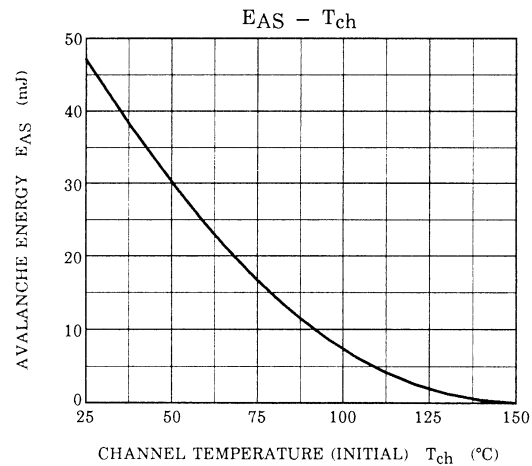
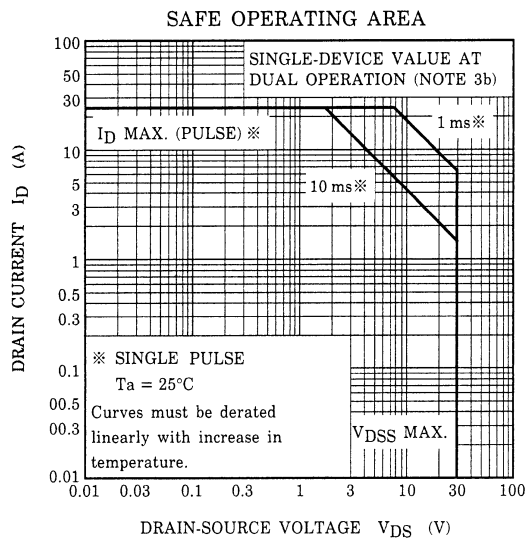
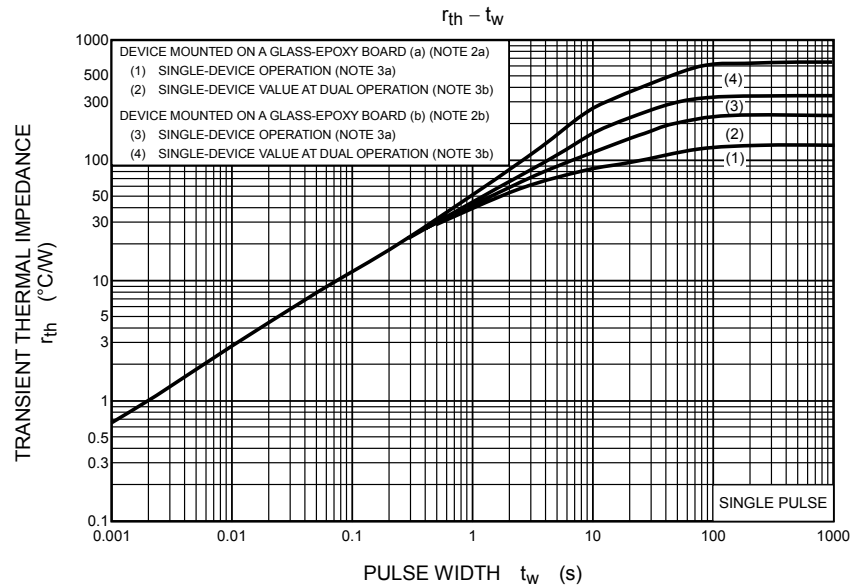
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		IGSS	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0 \text{ V}$	—	—	$\pm 10$	$\mu\text{A}$
Drain cut-OFF current		IDSS	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	—	—	10	$\mu\text{A}$
Drain-source breakdown voltage		$V_{(BR) DSS}$	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	30	—	—	V
		$V_{(BR) DSX}$	$I_D = 10 \text{ mA}, V_{GS} = -20 \text{ V}$	15	—	—	
Gate threshold voltage		$V_{th}$	$V_{DS} = 10 \text{ V}, I_D = 1 \text{ mA}$	0.8	—	2.5	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = 4 \text{ V}, I_D = 3 \text{ A}$	—	22	32	$\text{m}\Omega$
		$R_{DS(ON)}$	$V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$	—	14	21	
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = 10 \text{ V}, I_D = 3 \text{ A}$	4	8	—	S
Input capacitance		$C_{iss}$	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	—	1700	—	$\text{pF}$
Reverse transfer capacitance		$C_{rss}$		—	260	—	
Output capacitance		$C_{oss}$		—	380	—	
Switching time	Rise time	$t_r$	 <p><math>I_D = 3.0 \text{ A}</math>  <math>R_L = 5.0 \Omega</math>  <math>V_{DD} \approx 15 \text{ V}</math>  <math>\text{Duty} \leq 1\%, t_w = 10 \mu\text{s}</math></p>	—	10	—	ns
	Turn-ON time	$t_{on}$		—	20	—	
	Fall time	$t_f$		—	35	—	
	Turn-OFF time	$t_{off}$		—	120	—	
Total gate charge (Gate-source plus gate-drain)		$Q_g$	$V_{DD} \approx 24 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$	—	40	—	nC
Gate-source charge		$Q_{gs}$		—	28	—	
Gate-drain ("miller") charge		$Q_{gd}$		—	12	—	

## Source-Drain Ratings and Characteristics (Ta = 25°C)

Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Drain reverse current	Pulse (Note 1)	$I_{DRP}$	—	—	—	24	A
Forward voltage (diode)		$V_{DSF}$	$I_{DR} = 6 \text{ A}, V_{GS} = 0 \text{ V}$	—	—	-1.2	V







$T_{ch} = 25^{\circ}\text{C}$  (Initial)

Peak  $I_{AR} = 4.5 \text{ A}$ ,  $R_G = 25 \Omega$   $E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$

$V_{DD} = 24 \text{ V}$ ,  $L = 1.0 \text{ mH}$

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